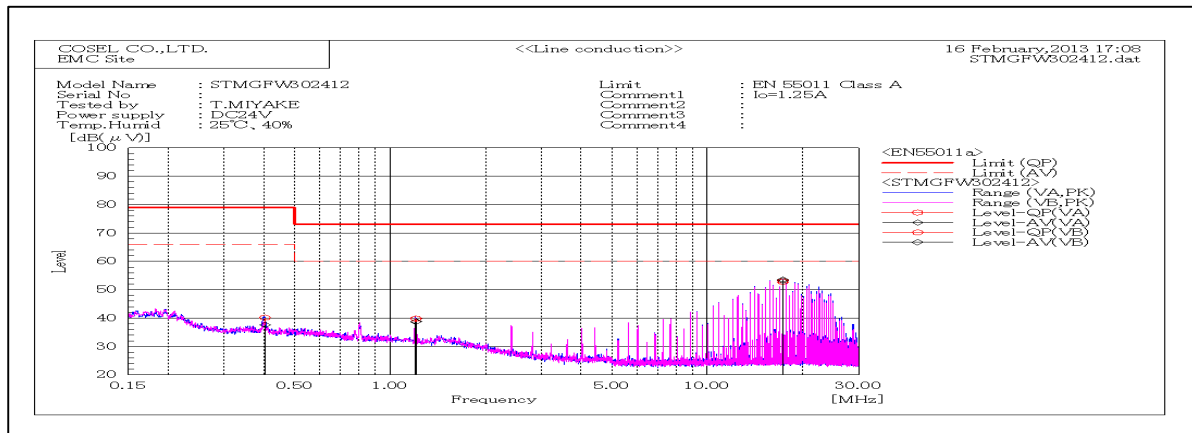
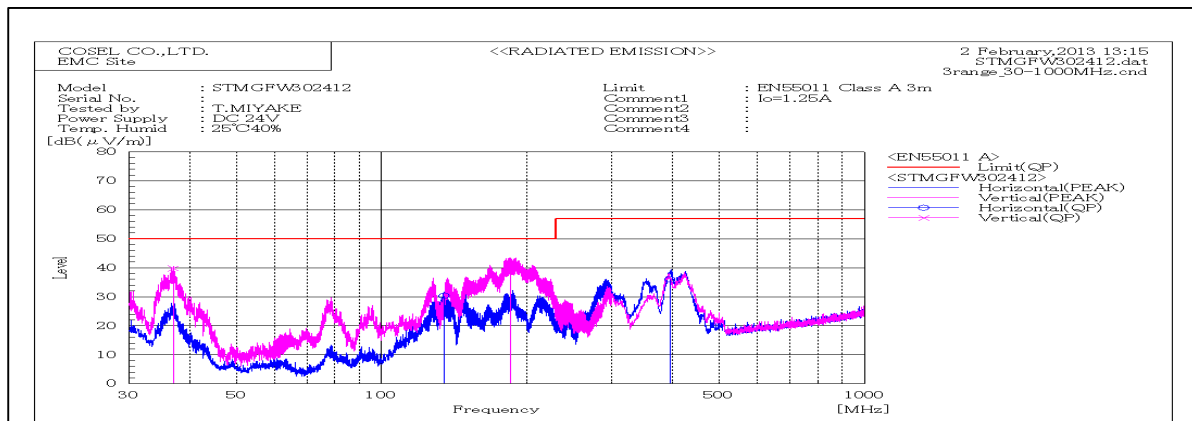


DATA SHEET		Date	18-Feb-13
Model	STMGFW302412	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake



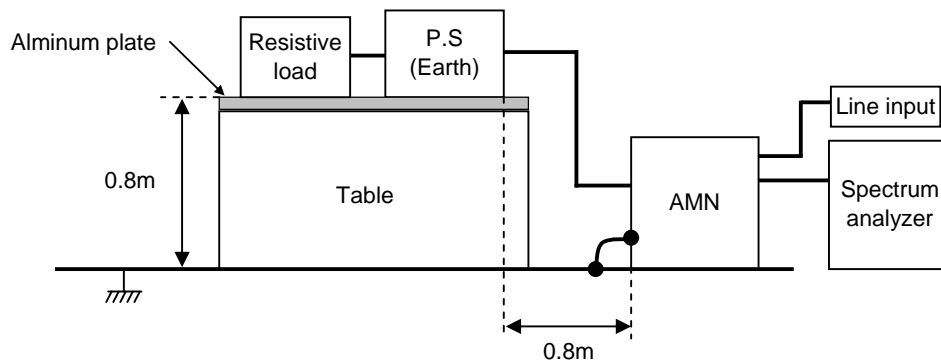
Frequency MHz	Harm	Line Phase	Reading dB(uV)		Factor dB	Level dB(uV)		Limit dB(uV)		Margin dB		Pass/ Fail	Remark
			QP	AV		QP	AV	QP	AV	QP	AV		
0.40367		VA	20.1	17.5	20.1	40.2	37.6	79	66	38.8	28.4	Pass	
1.20777		VB	19.6	18.6	20.2	39.8	38.8	73	60	33.2	21.2	Pass	
1.20596		VA	19.6	18.6	20.2	39.8	38.8	73	60	33.2	21.2	Pass	
17.3		VB	31.7	32	21.1	52.8	53.1	73	60	20.2	6.9	Pass	
17.2997		VA	32	32.4	21.2	53.2	53.6	73	60	19.8	6.4	Pass	



Frequency MHz	Polarization	Stability	Reading dB(uV)		Space Loss dB	Level dB(mW)		Limit dB(mW)	Margin dB	Pass/Fail	Height cm	Angle deg	Remark
			QP	AV		QP	AV						
37.07	V	Stable	55.1	-15.3		39.8		50	10.2	Pass	101	350	
134.595	H	Stable	50.3	-19.9		30.4		50	19.6	Pass	156	273	
184.55	V	Stable	57.3	-15.9		41.4		50	8.6	Pass	106	307	
395.725	H	Stable	47.8	-11.8		36		57	21	Pass	103	74	

DATA SHEET		Date	18-Feb-13
Model	Circuit used for measurement	Temp.	25 degreeC
Test	EMI Line conduction & Radiated emission	Humid.	40 %RH
		Tested by	T.Miyake

1. Line conduction



2. Radiated emission

